# Double Parton Scattering Measurements at the CMS Experiment

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### Overview

#### Introduction on double-parton scattering

#### DPS experiments at CMS

- Study of DPS using W + 2-jet events in proton-proton collisions at √s = 7 TeV
- Measurement of four-jet production in proton-proton collisions at sv = 7 TeV
- Studies of inclusive four-jet production with two b-tagged jets in proton-proton collisions at 7 TeV
- Evidence for WW production from double-parton interactions in proton-proton collisions at  $\sqrt{s} = 13 \text{ TeV}$

#### Conclusion



## **Double Parton Scattering**

DPS cross section: factorisation formula

*Cross section* = *parton level cross sections* x *double parton distributions* 

$$\frac{d\sigma_{DPS}}{dx_A dx_B dx_A' dx_B'} = m\hat{\sigma}_A \hat{\sigma}_B \int d^2 \boldsymbol{y} \, F(x_A, x_B, \boldsymbol{y}) F(x_A', x_B', \boldsymbol{y})$$

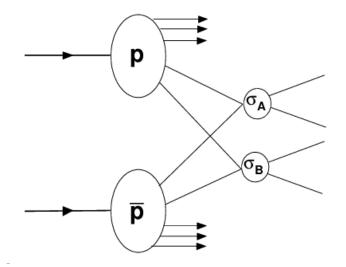
- $\hat{\sigma}_A$  and  $\hat{\sigma}_B$  parton level cross sections
- m is a combinatorial factor, ½ if processes are identical
- $F(x_A, x_B, y)$  is the double parton distribution function
- y is the transverse distance between the partons or impact parameter

Assume that  $F(x_A, x_B, y) = f(x_A)f(x_B)G(y)$  and where

- f(x) is the standard single parton distribution func
- G(y) is the transverse part of the double parton distribution and the same for all partons

The differential cross section becomes

$$\frac{d\sigma_{DPS}}{dx_A dx_B dx_A' dx_B'} = m \cdot \hat{\sigma}_A f(x_A) f(x_A') \cdot \hat{\sigma}_B f(x_B) f(x_B') \cdot \int d^2 \mathbf{y} G(\mathbf{y})$$



## **Double Parton Scattering**

Where  $\hat{\sigma}f(x)f(x')$  is the differential cross section for a single parton scattering event, which results in the pocket formula for DPS

$$\frac{d\sigma_{DPS}}{dx_1 dx_2 dx_1' dx_2'} = \frac{m}{\sigma_{eff}} \frac{d\sigma_1}{dx_1 dx_1'} \frac{d\sigma_2}{dx_2 dx_2'}$$

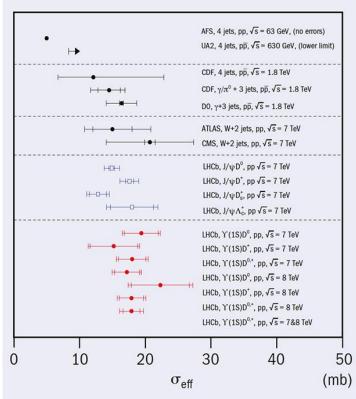
Where 
$$\frac{1}{\sigma_{eff}} = \int d^2 y G(y)$$

In this approach the parameter  $\sigma_{eff}$  is independent of the final state and measurement of effective area parameter  $\sigma_{eff}$  gives insight in hadron structure in the transversal plane!

Examine variables that exhibit distinctive behaviour for SPS and DPS processes

Different final states in DPS measurements at CMS

- W + 2 jets
- 4 jets
- $\gamma + 3$  jets
- 2b + 2 jets
- Same-sign WW



## Study of DPS using W + 2-jet events in protonproton collisions at $\sqrt{s} = 7$ TeV

Measure DPS sensitive variable

$$\Delta p_T^{rel} = \frac{|\vec{p}_T(j_1) + \vec{p}_T(j_2)|}{|\vec{p}_T(j_1)| + |\vec{p}_T(j_2)|}$$

 $\rightarrow$  Jets back-to-back in DPS, variable expected to be small ( $\approx$  0)

$$\Delta S = \arccos\left(\frac{\vec{p}_T(\mu, E_{T,miss}) \cdot \vec{p}_T(j_1, j_2)}{|\vec{p}_T(\mu, E_{T,miss})| \cdot |\vec{p}_T(j_1, j_2)|}\right)$$

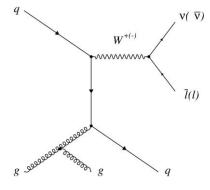
No correlation between particle pairs for DPS, distribution will be flat

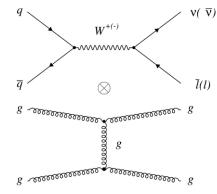


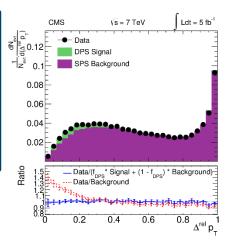
Fully corrected variables fitted with signal and background template by using a binned likelihood method

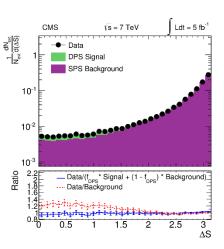


- $f_{DPS} = 0.055 \pm 0.002$  (stat.)  $\pm 0.014$  (syst.)
- $\sigma_{eff} = 20.7 \pm 0.8 \text{ (stat.)} \pm 6.6 \text{ (syst.)} \text{ mb}$









## Measurement of four-jet production in proton-

proton collisions at  $\sqrt{s} = 7$  TeV

Measure DPS sensitive variable

$$\Delta p_T^{rel} = \frac{|\vec{p}_T(j_3) + \vec{p}_T(j_4)|}{|\vec{p}_T(j_3)| + |\vec{p}_T(j_4)|}$$

$$\Delta S = \arccos\left(\frac{\vec{p}_T(j_1, j_2) \cdot \vec{p}_T(j_3, j_4)}{|\vec{p}_T(j_1, j_2)| \cdot |\vec{p}_T(j_3, j_4)|}\right)$$

$$\Delta \varphi_{34} = |\varphi(j_3) - \varphi(j_4)|$$

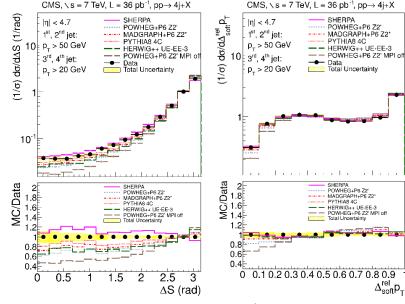
Differential cross section determined

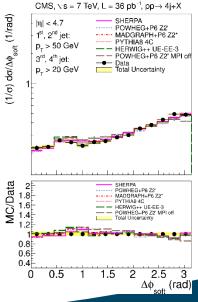
$$\sigma_{4j} = 330 \pm 5 \text{ (stat.)} \pm 45 \text{ (syst.)} \text{ pb}$$

Normalised differential cross section in function of the

variables compared to different MC models with and without MPI

Models only give proper description in some regions of the phase space







## Measurement of four-jet production in protonproton collisions at $\sqrt{s} = 7$ TeV

New method for extraction of  $\sigma_{eff}$  applied :

Tuning method (doi:10,1140/epjc/s10052-016-3988-x):

DPS sensitive variables fitted directly and  $\sigma_{eff}$  determined from the models

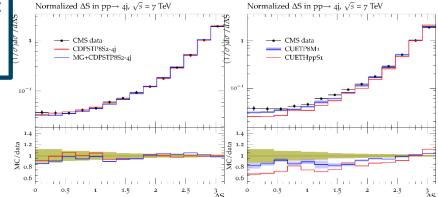
| CMS Tune              | $\sigma_{ m eff}({ m mb})$ at 7 TeV | $\sigma_{ m eff}({ m mb})$ at 13 TeV |
|-----------------------|-------------------------------------|--------------------------------------|
| CUETP8S1-CTEQ6L1      | $27.8^{+1.2}_{-1.3}$                | $29.9^{+1.6}_{-2.8}$                 |
| CUETP8S1-HERAPDF1.5LO | $29.1^{+2.2}_{-2.0}$                | $31.0^{+3.8}_{-2.6}$                 |
| CUETP8M1              | $26.0^{+0.6}_{-0.2}$                | $27.9^{+0.7}_{-0.4}$                 |
| CUETHppS1             | $15.2^{+0.5}_{-0.6}$                | $15.2^{+0.5}_{-0.6}$                 |
| CDPSTP8S1-4j          | $21.3^{+1.2}_{-1.6}$                | $21.8^{+1.0}_{-0.7}$                 |
| CDPSTP8S2-4j          | $19.0^{+4.7}_{-3.0}$                | $22.7^{+10.0}_{-5.2}$                |

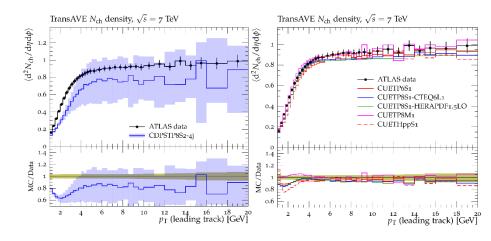
#### 2 DPS tunes:

- CDPSTP8S1-4j: only MPI:expPow varied
- CDPSTP8S2-4j: MPI:pT0Ref, MPI:ecmPow and ColourReconnection:range additionally varied

DPS and UE tunes not completely compatible:

- DPS sensitive observables not quite as good described by UE tunes
- Difficulty of describing soft and hard MPI within the current frameworks







# Studies of inclusive four-jet production with two b-tagged jets in proton-proton collisions at $\sqrt{s} = 7$ TeV

Measure DPS sensitive variable

$$\Delta p_T^{rel} = \frac{|\vec{p}_T(light_1) + \vec{p}_T(light_2)|}{|\vec{p}_T(light_1)| + |\vec{p}_T(light_2)|}$$

$$\Delta S = \arccos\left(\frac{\vec{p}_T(bottom_1, bottom_2) \cdot \vec{p}_T(light_1, light_2)}{|\vec{p}_T(bottom_1, bottom_2)| \cdot |\vec{p}_T(light_1, light_2)|}\right)$$

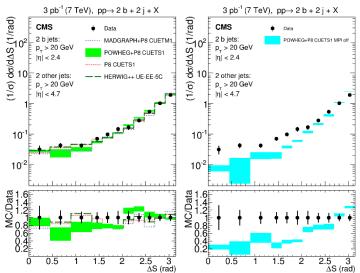
$$\Delta \varphi_{light} = |\varphi(light_1) - \varphi(light_2)|$$

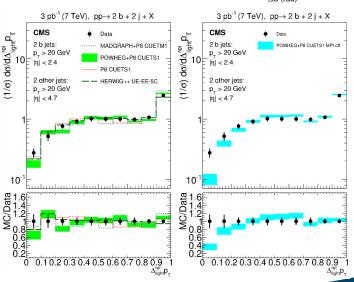
Differential cross section determined

$$\sigma_{2b+2j} = 69 \pm 3 \text{ (stat.)} \pm 24 \text{ (syst.)} \text{ pb}$$

Normalised differential cross section will be compared to different MC models

- Good agreement between MC models except Powheg+P8 with no MPI
- Differences in description in DPS sensitive areas
- First sign of DPS sensitivity in multi-jet final state with heavy-quarks





CMS PAS SMP-18-015

Evidence for WW production from double-parton interactions in proton-proton collisions at  $\sqrt{s} = 13 \text{ TeV}$ 

#### Motivation

W boson production: benchmark process at LHC and golden channel for DPS production

Quark initiated

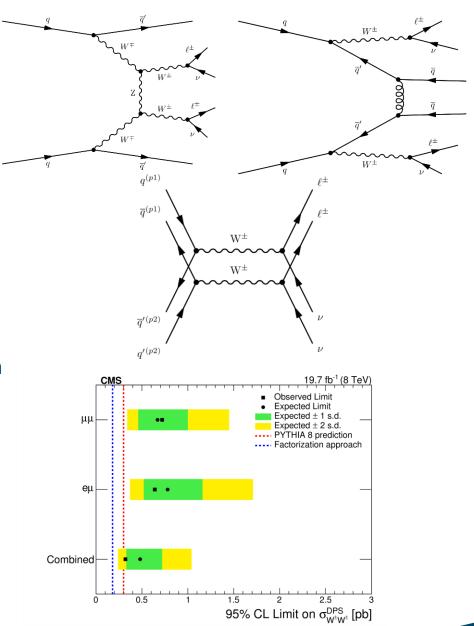
Sensitive to longitudinal quark polarizations

Not sensitive to pileup effects and clean final state

DPS WW process constitutes a background in new physics at LHC

Previous study at  $\sqrt{s} = 8 \text{ TeV}$  (doi:10.1007/JHEP02(2018)032)

- First search for same-sign WW production through DPS
- No significant excess of events observed above the expected SPS yield
- 95% confidence level lower limit of 12.2 mb on  $\sigma_{eff}$  or an upper constraint of 0,32 pb on the cross section



### Signal and Background Processes

#### Signal

- Same-sign lepton pairs (eμ, μμ) coming from W boson pairs
- MET from decay of W bosons

#### Background

- Diboson processes
  - WZ as dominant background
  - Wγ, Wγ\*, Zγ, ZZ and WWW as additional processes
  - One of the leptons escapes detector acceptance
  - Estimation is MC driven
- Electron charge flips
  - $Z \rightarrow \tau \tau$  with letponic decay  $\tau$
  - Data driven estimation

- Production of fake leptons
  - QCD multijet and W+jets: misidentification of jets as leptons
  - Top pair+jets: leptonic decay of top quarks
  - Data driven estimation through fake rate method

# Event Selection and Multi-Variate Analysis using a Boosted Decision Tree (BDT) Training

#### Variables:

- $p_T^{l1}$  and  $p_T^{l2}$
- $\Delta \varphi(l_1, l_2)$

•  $E_T^{miss}$ 

•  $\Delta \varphi(l_1, E_T^{miss})$ 

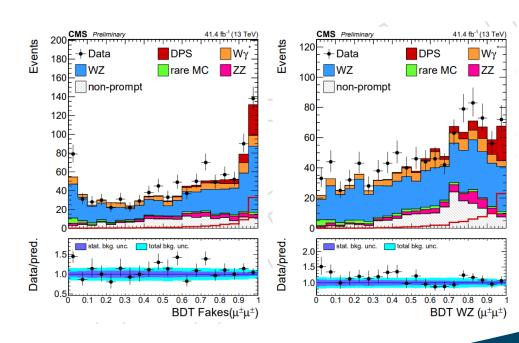
 $\bullet M_{T2}^{ll}$ 

- $\Delta \varphi(l_1 l_2, l_2)$
- $\bullet m_T(l_1, l_2)$
- $\eta_1 \cdot \eta_2$
- $m_T(l_1, E_T^{miss})$  |r
  - $\bullet |\eta_1 + \eta_2|$

## MVA based on BDT technique to enhance signal sensitivity

- 2 BDTs trained
  - WZ background
  - Fake lepton background
- Same variables used in both BDTs
- The BDTs determine a 2D distribution

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two leptons: e^{\pm}\mu^{\pm} or \mu^{\pm}\mu^{\pm} p_{\mathrm{T}}^{\ell_{1}} > 25\,\mathrm{GeV} , p_{\mathrm{T}}^{\ell_{2}} > 20\,\mathrm{GeV} |\eta_{\mathrm{e}}| < 2.5, |\eta_{\mu}| < 2.4 p_{\mathrm{T}}^{\mathrm{miss}} > 15\,\mathrm{GeV} N_{\mathrm{jets}} < 2\,(p_{\mathrm{T}} > 30\,\mathrm{GeV} and |\eta| < 2.5) N_{\mathrm{b\text{-}tagged\ jets}} = 0\,(p_{\mathrm{T}} > 25\,\mathrm{GeV} and |\eta| < 2.4) veto on additional e, \mu, and \tau_{\mathrm{h}}
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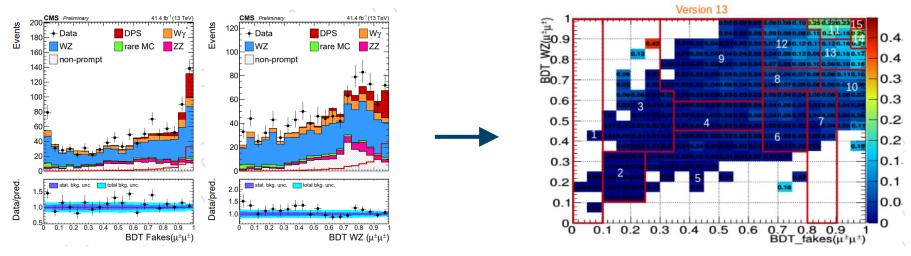


## Constructing the Final Classifier

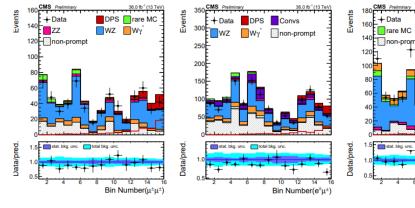
2D BDT distribution mapped into 1D classifier

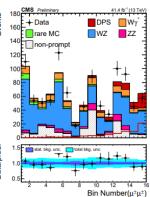
Determination of bins through iterative process

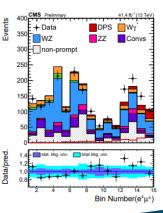
→ Make discrimination between signal and background as large as possible



#### Pre-fit results (2016 left, 2017 right)

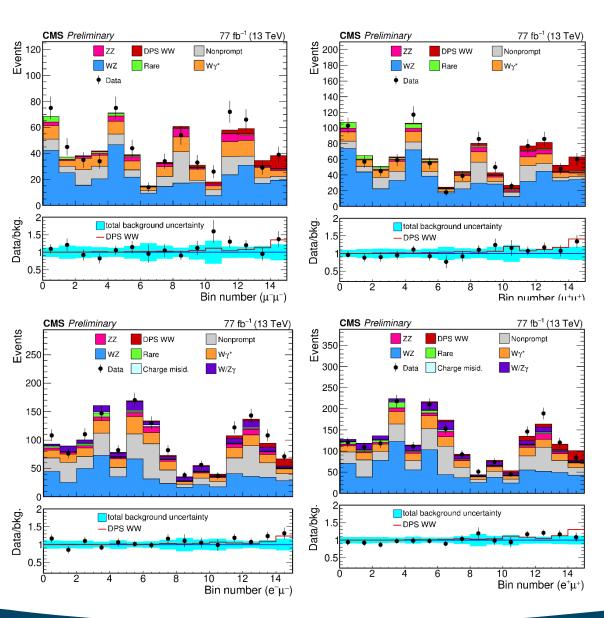








## Resulting Distributions (post-fit)



Maximum likelihood fit performed to final classifier Different final states fit separately

Better signal sensitivity due to W production asymmetry

## Extraction of $\sigma_{eff}$

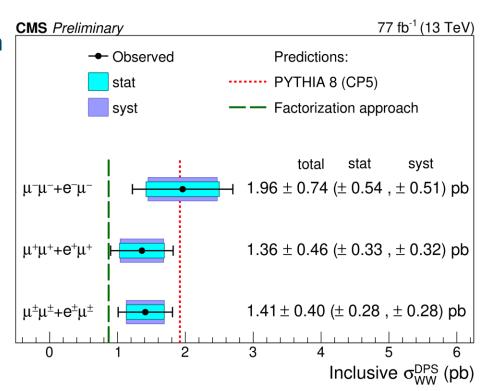
After training two multivariate classifiers and combining their results a first measurement of DPS same sign WW is achieved

#### Model predictions:

- Pythia 8 (CP5)
- Factorized approach by using pocket formula with:
  - Inclusive W production cross section
  - $\sigma_{eff}$  = 20.7 ± 6.6 mb

Cross sections have been deducted for both the lepton pair configurations and their combination





### Conclusion

- Multiple studies of different DPS processes have been performed for different final states at the CMS experiment
- Within these final states a proper choice of the many DPS sensitive variables needs to be made
- $\blacksquare$  Proper understanding of the background processes is needed to obtain a value for  $\sigma_{eff}$ , multiple techniques exist
  - Template method
  - Tuning method
  - MVA using BDT